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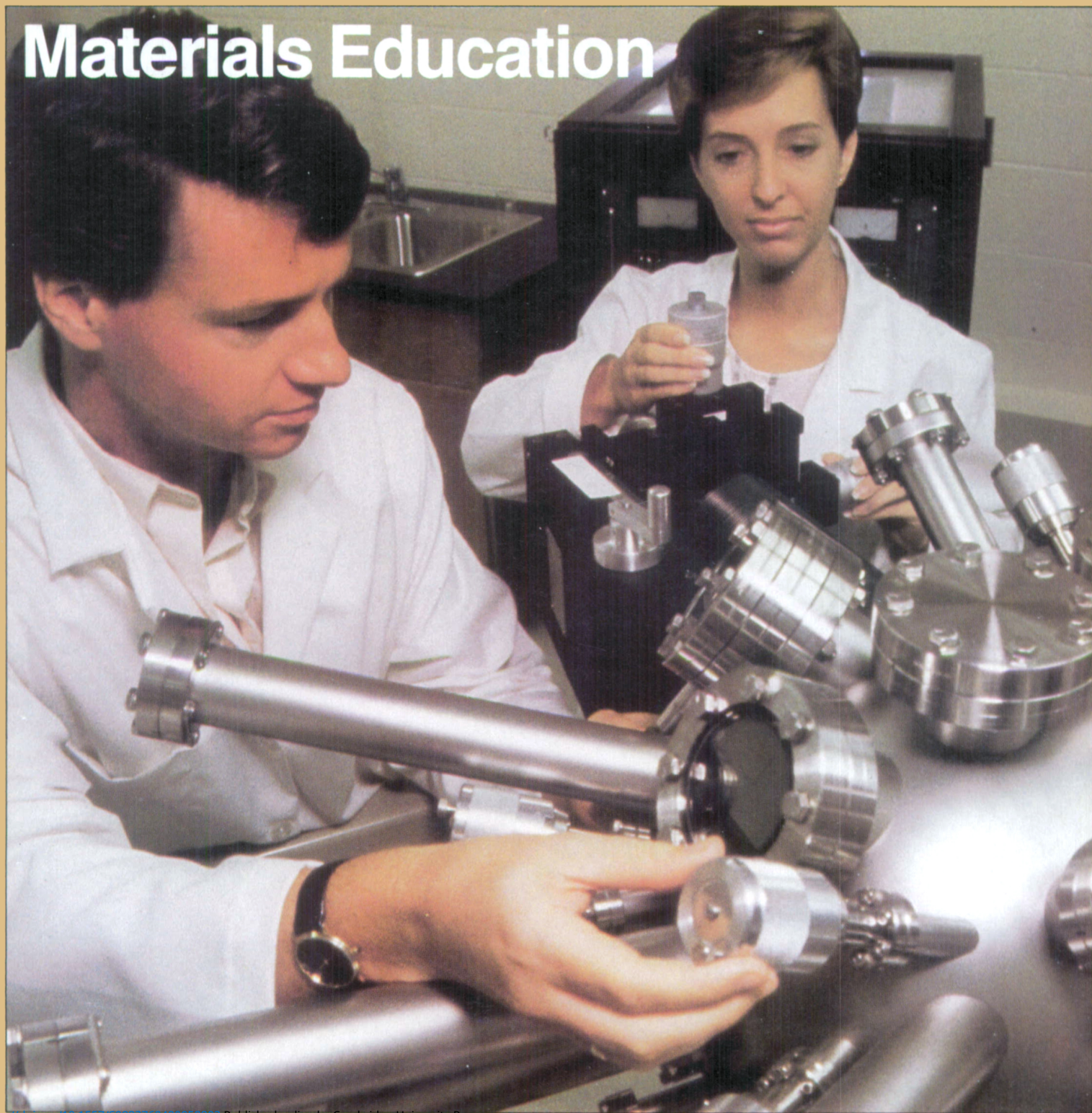
BULLETIN

August 1990

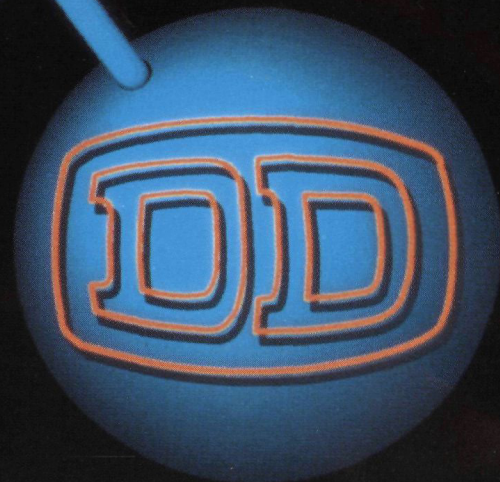
Volume XV, Number 8

Serving the International Materials Research Community

Materials Education



A NEW CLUSTER IS BORN



General Ionex acquired by High Voltage Engineering Europa B.V.

In December 1987 High Voltage Engineering Europa B.V. (HVEE) acquired Dowlish Developments Ltd (DD), an accelerator tube manufacturer located in the United Kingdom.

On April 10, 1989, HVEE purchased the General Ionex Analytical Product Group from Genus Inc. based in the United States.

Through this acquisition HVEE positions itself as the largest and most diverse manufacturer of particle accelerators for the scientific and industrial research communities.

The acquired General Ionex (GI) product lines, which include the Tandetron accelerator systems and Model 4175 RBS Analyser, will be manufactured in HVEE's new, well-equipped facility in Amersfoort, The Netherlands.

World wide marketing of all products from HVEE, DD and GI will originate from HVEE Amersfoort with sales and service offices in the USA, Europe and Japan.

After addition of the newly acquired products HVEE's product lines include:

– *Ion Accelerator Systems*

- Air insulated accelerators up to 500 kV
- Single ended Van de Graaff accelerators up to 4 MV
- Tandem Tandetron accelerators up to 3 MV/TV

– *Research ion implanters*

- Beam energies 10 keV-9 MeV and higher

– *Systems for ion beam analysis*

- Systems for RBS, PIXE, PIGE, NRA, ERD, MACS and MEIS

– *Components*

- HV power supplies, electron and ion accelerator tubes, ion sources beamline components, beam monitoring equipment, UHV sample manipulators, etc.

For further information on this transaction and product literature please contact HVEE in Amersfoort/NL.



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MATERIALS EDUCATION

- 18 Materials Education—
A Challenge**
R. Abbaschian, Guest Editor
- 23 Making Education in
Materials Science and
Engineering Attractive to
Undergraduate Students**
G.C. Farrington
- 27 Identity of and Need for
Undergraduate Materials
Science and Engineering
Education**
J. DuBow
- 31 The Emerging Undergrad-
uate Curricula in Materials
Science and Engineering**
G.L. Liedl
- 35 Proposal for a Generic
Materials Processing Course**
M.C. Flemings, K.V. Jensen, and
A. Mortensen
- 37 The Undergraduate Physics
and Materials Science
Connection**
D.F. Holcomb
- 40 Materials in the
Undergraduate Chemistry
Curriculum**
M.S. Whittingham
- 46 The College-Wide
Interdisciplinary Materials
Science and Engineering
Graduate Program**
D.L. Bourell and H.L. Marcus

- 49 From Concept to
Commerce: The Challenge
of Technology Transfer
in Materials**
L.L. Hench
- 54 NSF Workshop on
Undergraduate Curriculum
Development in Materials:
A Synopsis of the Report**
R.J. Reynik

MRS NEWS

- 58 San Francisco Report:
Materials Science Registers
High on the Scale**
- 67 A Personal Perspective on
Short Courses**
- 68 Call for Papers—1991 MRS
Spring Meeting**
- 70 Hays, Marinero, and
Thompson to Chair 1991
MRS Spring Meeting**



DEPARTMENTS

- 5 Letter from the President**
- 7 Materials Matters**
- 8 Research/Researchers**
- 14 Research Resources**
- 15 From Washington**
- 17 Editor's Choice**
- 71 Section News**
- 72 Chapter News**
- 73 Conference Reports**
- 76 Journal of Materials
Research**
- 78 Historical Note**
- 79 Advertisers in This Issue**
- 80 Book Reviews**
- 82 Upcoming Conferences**
- 83 Calendar**
- 86 Classified**

ON THE COVER: Robert M. Park (left), an associate professor in the Department of Materials Science and Engineering, University of Florida, and graduate research assistant Mary-Jane Troffer prepare to grow an epitaxial layer of the wide-bandgap II-VI compound semiconductor, ZnSe, in a custom-designed molecular beam epitaxy (MBE) system. Materials research is currently directed toward solving problems associated with doping ZnSe, both n- and p-type, with a view to fabricating light-emitting devices that operate in the blue region of the visible spectrum. Is it valuable for students to be involved in commercializing R&D efforts? For more about tech transfer and the academic setting, see the article by L.L. Hench on p. 49.

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ABOUT THE MATERIALS RESEARCH SOCIETY

The Materials Research Society (MRS) is a nonprofit scientific association founded in 1973 to promote interdisciplinary goal-oriented basic research on materials of technological importance. Membership in the Society includes more than 9,500 scientists from industrial, government, and university research laboratories in the United States and more than 25 countries.

The Society's interdisciplinary approach to the exchange of technical information is qualitatively different from that provided by single-discipline professional societies because it promotes technical exchange across the various fields of science affecting materials development. MRS sponsors two major international annual meetings encompassing approximately 40 topical symposia, as well as numerous single-topic scientific meetings each year. It recognizes professional and technical excellence, conducts short courses, and fosters technical exchange in various local geographic regions through Section activities and University Chapters.

MRS is an Affiliated Society of the American Institute of Physics and participates in the international arena of materials research through associations with professional organizations such as European MRS.

MRS publishes symposium proceedings, the *MRS BULLETIN*, *Journal of Materials Research*, and other current scientific developments.

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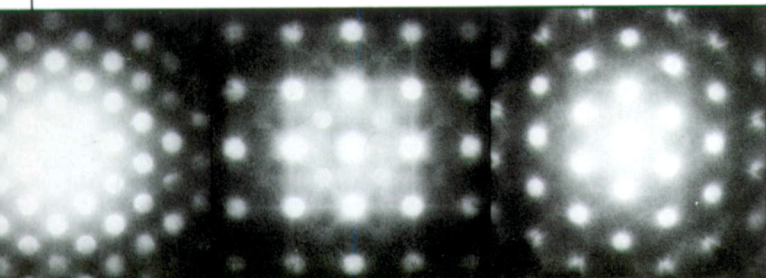
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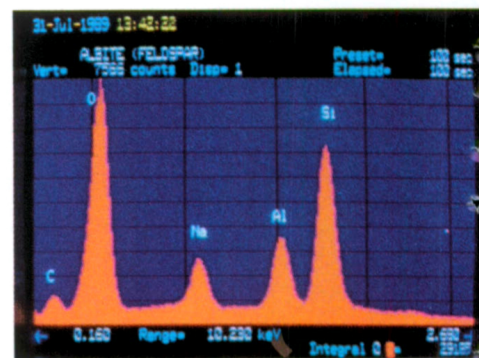
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